

			02.11.2011
RefMat No Type_of_RefMat	50%	Included in DMAR Database: Green 1> YES Blue 0> NO	Category 1 Film Thickness Category 2 Category 3 Category 4 Category 5
Name of RM: WFTS			
Description Thickness Standards, Tungsten Film, For best performance with sonar technology, an oxide layer 100 nm thick is added between the silicon substrate and the metal film. traceable to NIST Link http://www.vlsistd.com/products/film/metal.asp?SID=98			
Certified Qantities			
	Certified (Qantities MeanValue	200 nm Uncertainty
		MeanValue	Uncertainty
		MeanValue	Uncertainty
		MeanValue	Uncertainty
		MeanValue Page 1	Uncertainty
Calibration of Calibration of Calibration of Calibration of Calibration of	optoacoustic measurement tools		Characterised by Characterised by Characterised by Characterised by Characterised by Characterised by
2 Provider No Provider No			
Provider No	Web address http	://www.vlsistanda	<u>rds.com</u>
Provider	VLSI Standards, Inc.		
Contact Person	Marc Helvey, ext. 108	Country	USA
Email	sales.support@vlsistd.com	City	San Jose
Phone	(408) 428-1800	City Code	CA 95134-2006
		Street + No	3087 North First Street